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CONFIRMATION NO. 3875

<b>SERIAL NUMBER</b> 10/672,558	<b>FILING OR 371(c) DATE</b> 09/26/2003 <b>RULE</b>	<b>CLASS</b> 356	<b>GROUP ART UNIT</b> 2877	<b>ATTORNEY DOCKET NO.</b> LUXT.118US2	
<b>APPLICANTS</b> Charles W. Schietinger, Portland, OR; Ann N. Hoang, San Jose, CA; Dmitry V. Bakin, San Jose, CA;					
<b>** CONTINUING DATA *****</b> This application is a DIV of 09/577,795 05/24/2000 PAT 6,654,132 which is a CIP of 09/317,697 05/24/1999 PAT 6,570,662					
<b>** FOREIGN APPLICATIONS *****</b>					
<b>IF REQUIRED, FOREIGN FILING LICENSE GRANTED** SMALL ENTITY **</b> ** 01/15/2004					
Foreign Priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 (a-d) conditions <input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance Verified and Acknowledged _____ Examiner's Signature _____ Initials _____		<b>STATE OR COUNTRY</b> OR	<b>SHEETS DRAWING</b> 15	<b>TOTAL CLAIMS</b> 35	<b>INDEPENDENT CLAIMS</b> 6
<b>ADDRESS</b> 21839					
<b>TITLE</b> OPTICAL TECHNIQUES FOR MEASURING LAYER THICKNESSES AND OTHER SURFACE CHARACTERISTICS OF OBJECTS SUCH AS SEMICONDUCTOR WAFERS					
<b>FILING FEE RECEIVED</b> 2608	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees ( Filing ) <input type="checkbox"/> 1.17 Fees ( Processing Ext. of time ) <input type="checkbox"/> 1.18 Fees ( Issue ) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit		